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	Application Number		10536483	
INFORMATION DIGGLOCATE	Filing Date		2005-05-24	
INFORMATION DISCLOSURE	First Named Inventor Bruce		ce B. Doris	
STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Art Unit		2826	
(Not for Submission ander or of it iso)	Examiner Name Benja		jamin T. Liu	
	Attorney Docket Numb	er	6798	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Application Number		10536483
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First Named Inventor	Bruce	B. Doris
Art Unit		2826
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Attorney Docket Numb	er	6798

Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.							
BTL	1	A. Shimizu et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement", International Electron Devices Meeting 2001. IEDM Technical Digest. 2001 IEEE, pp. 19.4.1-19.4.4.							
BTL	2	S. Ito et al., "Effect of Mechanical Stress Induced by Etch-Stop Nitride: Impact on Deep-Submicron Transistor Performance", Microelectronics and Reliability, Elsevier Science Ltd., GB, vol. 42, no. 2, February 2002, pages 201-209.							
BTL	3 S. Ito et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design", IEDM Technical Digest, 2000 IEEE, pp. 10.7.1-10.7.4.								
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		4,853,076	8-1-89	Tsaur,	et al.				
		4,855,245	8-8-89	Neppl,	, et al.				
V		4,952,524	8-28-90	Lee, et	al.				
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BTL		US 2001/0009784 A1	7-26-01	Ma, et	al.				Ura
		US 2002/0063292 A1	5-30-02	Armstr	rong, et al.	1			
		US 2002/0074598 A1	6-20-02	Doyle, e	et al.				
V		US 2002/0086472	7-4-02	Roberd	ls, et al.				
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Doris, et al.

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*EXAMINER INTITAL	REF	DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS		G DATE ROPRIATE	
BTL		4,958,213	9-18-90	Eklun	d, et al.					
BTL		5,006,913	4-9-91	Sugah	ara, et al.					
BTL		5,060,030	10-22-91	Hoke,	et al.					
BTL		5,081,513	1-14-92	Jackso	n, et al.					
BTL		5,108,843	4-28-92	Ohtak	a, et al.					
U.S. PATENT APPLICATION PUBLICATIONS										
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING	G DATE OPRIATE	
BTL		US 2002/0086497 A1	7-4-02	Kwok						
BTL		US 2002/0090791 A1	7-11-02	Doyle, et al.						
BTL		US 2003/0032261 A1	2-13-03	Yeh, et al.						
BTL		US 2003/0040158 A1	2-27-03	Saitoh						
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BTL		Gregory Scott, et al., "NN International Electron De	10S Drive Curr vices Meeting, 3	ent Redu 4.4.1, IEI	ction Caused by Transistor EE, September 1999.	Layout and T	rench Isolation	Induced	Stress."	
BTL		F. Ootsuka, et al., "A Hig Application." Internation	hly Dense, High- al Electron Dev	Perform ices Meet	ance 130nm Node CMOS To ing, 23.5.1, IEEE, April 200	echnology for 0.	Large Scale S	ystem-on-	a-Chip	
EXAMINER		/Benjamin Tzu-Hung Liu			DATE CONSIDERED / ((09/13/2006)				

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BTL		5,134,085	7-28-92	Gilgen, et al.				
BTL		5,310,446	5-10-94	Konishi, et al.				
BTL		5,354,695	10-11-94	Leedy				
BTL		5,371,399	12-6-94	Burroughes, et al.				
BTL		5,391,510	2-21-95	Hsu, et al.				
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BTL		US 2003/0057184 A1	3-27-03	Yu, et al.				
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BTL		5,459,346	10-17-95	Asakaw	a, et al.					
BTL		5,471,948	12-5-95	Burrou	ghes, et al.					
BTL		5,557,122	9-17-96	Shrivas	tava, et al.					
BTL		5,561,302	10-1-96	Candela	ıria					
BTL		5,565,697	10-15-96	Asakaw	a, et al.					
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BTL		G. Zhang, et al., "A New IEEE Transactions on E	v 'Mixed-Mode' R llectron Devices, v	teliability) vol. 49, no.	Degradation Mechanism 12, December 2002, pp.	In Advanced S 2151-56.	and SiGe Bip	olar Transi	istors."	
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			U.	S. PATENT DOCUMENTS			
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BTL		5,683,934	11-4-97	Candelaria			
BTL		5,840,593	11-24-98	Leedy			
BTL		5,861,651	1-19-99	Brasen, et al.			
BTL		5,880,040	3-9-99	Sun, et al.			
BTL		5,940,716	8-17-99	Jin, et al.			
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BTL		5,940,736	8-17-99	Brady, e	et al.				
BTL		5,946,559	8-31-99	Leedy					
BTL		5,960,297	9-28-99	Saki					
BTL		5,989,978	11-23-99	Peidous					
BTL		6,008,126	12-28-99	Leedy					
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BTL		H. Li, et al., "Design of Systems." 2003 IEEE (W-Band VCOs w GaAs Digest, pp. 2	ith High Oc 63-66.	utput Power for Poten	tial Application i	n 77 GHz Auto	motive Ra	dar
BTL		H. Wurzer, et al., "Ann Devices, vol. 41, no. 4, A	ealing of Degrade April 1994, pp. 533	d npn-Tran I-38.	nsistors- Mechanisms a	and Modeling." 1	EEE Transact	ions on El	ectron
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BTL		6,025,280	2-15-00	Brady,	, et al.		ļ		
BTL		6,046,464	4-4-00	Schetzi	ina		<u>'</u>		
BTL		6,066,545	5-23-00	Doshi, e	et al.				
BTL	<u></u>	6,090,684	7-18-00	Ishitsu	ka, et al.				-
BTL		6,107,143	8-22-00	Park, et	t al.				
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BTL		B. Doyle, et al., "Recove Letters, vol. 13, no. 1, J	ery of Hot-Carrie anuary 1992, pp.	er Damage . 38-40.	in Reoxidized Nitrided Ox	ide MOSPETs	." IEEE Elect	ron Device	;
BTL	1	H.S. Momose, et al., "A for Bi-CMOS." IEEE	nalysis of the Ter Transactions on I	mperature Electron De	Dependence of Hot-Carrie evices, vol. 41, no. 6, June 1	r-Induced Deg 994, pp. 978-9	radation in Bi	polar Tran	sistors
EXAMINER		/Benjamin Tzu-Hung	J Liu		DATE CONSIDERED	/ (09/13/20	006)		

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BTL		6,117,722	9-12-00	Wuu, et	t al.				
BTL		6,133,071	10-17-00	Nagai					
BTL		6,165,383	12-26-00	Chou					
BTL		6,221,735	4-24-01	Manley, et al.					
BTL		6,228,694	5-8-01	Doyle, e	t al.				
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/Benjamin Tzu-Hung Liu

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BTL		6,246,095	6-12-01	Brady,	et al.					
BTL		6,255,169	7-3-01	Li, et a	I.					
BTL		6,261,964	7-17-01	Wu, et	al.					
BTL		6,265,317	7-24-01	Chiu, e	t al.					
BTL		6,274,444	8-14-01	Wang						
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BTL		6,281,532	8-28-01	Doyle, e	et al.			IF APP	ROPRIATE		
BTL		6,284,623	9-4-01	Zhang,	et al.	 					
BTL		6,284,626	9-4-01	Kim							
BTL		6,319,794	11-20-01	Akatsu,	et al ·						
BTL		6,361,885	3-26-02	Chou	Chou						
			U.S. PATEN	T APPLICA	TION PUBLICATIONS						
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BTL		6,362,082	3-26-02	Doyle,	et al.				
BTL		6,368,931	4-9-02	Kubn,	et al.				
BTL		6,403,486	6-11-02	Lou					
BTL		6,403,975	6-11-02	Brunne	er, et al.				
BTL		6,406,973	6-18-02	Lee					
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Docket Number (Optional) PIS920020105 INFORMATION DISCLOSUR TATION Applicant(s) (Use several sheets if necessary) Doris, et al Filing Date Group Art Unit 11/25/02 To be assigned U.S. PATENT DOCUMENTS ENAMINER REF FILING DATE DOCUMENT NUMBER DATE NAME CLASS SUBCLASS INITIAL. IF APPROPRIATE BTL 6,461,936 10-8-02 von Ehrenwall 6,476,462 11-5-02 Shimizu, et al. BTL 6,483,171 11-19-02 Forbes, et al. BTL 6,493,497 12-10-02 Ramdani, et al. BTL 6,498,358 12-24-02 Lach, et al. BTL U.S. PATENT APPLICATION PUBLICATIONS EXAMINER FILING DATE REF DOCUMENT NUMBER DATE NAME Cl.ASS SUBCLASS INITIAL IP APPROPRIATE FOREIGN PATENT DOCUMENTS Translation REF DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS YES NO OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) **EXAMINER DATE CONSIDERED** / (09/13/2006) /Benjamin Tzu-Hung Liu EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO-A820 (also form PTO-1449) P09A/REV05

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BTL		6,531,740	3-11-03	Bosco,	et al.						
BTL		6,621,392	9-16-03	Volant,	et al.						
BTL		6,635,506	10-21-03	Volant,	et al.	-					
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BTL		6,342,410	1-29-02	Yu				IF AFFR	COPROATE
BTL		6,413,802	7-2-02	Hu, et a	I.				 -
BTL		6,433,609	8-13-02	Voldma	n				
BTL		6,458,662	10-1-02	Yu					
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